

Notice of References Cited	Application/Control No. 09/785,598	Applicant(s)/Patent Under Reexamination THALER ET AL.	
	Examiner Derrick W. Ferris	Art Unit 2663	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,032,261 A	02-2000	Hulyalkar, Samir N.	713/400
	B	US-5,621,895 A	04-1997	Weis et al.	370/407
	C	US-6,199,169 B1	03-2001	Voth, Duane J.	713/400
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	WEIDEMANN, Werner. "Application Critical Parameters for Rubidium Standards". IEEE. 27-29 May 1998. Pages 84-87.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.